


<b>Search Notes</b>  	<b>Application/Control No.</b>  10570053	<b>Applicant(s)/Patent Under Reexamination</b>  VISOZ ET AL.
	<b>Examiner</b>  SUNG AHN	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	346-350	12/16/2008	Sung Ahn

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search (Please view search history list)	12/16/2008	Sung Ahn
IEEE Explorer (Searched with similar key words used in EAST search)	12/16/2008	Sung Ahn
Double Patent Search (Searched with inventors name in eDAN bib)	12/11/2008	Sung Ahn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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